

## EDA321: Digital Design Solutions of Re-Exam - August 2013

### Question 1: (5 points)

Apply deMorgan Theorems to the expressions:

$$\overline{(A+B+C)D}$$

$$\overline{ABC+DEF}$$

$$\overline{A\bar{B}+\bar{C}D+EF}$$

$$\overline{\overline{A+B\bar{C}+D(E+\bar{F})}}$$

**Solution:**

$$\overline{(A+B+C) \cdot D} = \overline{A+B+C} \cdot \bar{D} = \bar{A} \cdot \bar{B} \cdot \bar{C} + \bar{D}$$

$$\overline{A \cdot B \cdot C + D \cdot E \cdot F} = \overline{A \cdot B \cdot C} \cdot \overline{D \cdot E \cdot F} = (\bar{A} + \bar{B} + \bar{C}) \cdot (\bar{D} + \bar{E} + \bar{F})$$

$$\overline{A \cdot \bar{B} + \bar{C} \cdot D + E \cdot F} = \overline{A \cdot \bar{B}} \cdot \overline{\bar{C} \cdot D} \cdot \overline{E \cdot F} = (\bar{A} + B)(C + \bar{D})(\bar{E} + \bar{F})$$

$$\overline{\overline{A+B\bar{C}+D(E+\bar{F})}} = \overline{(A+B\bar{C})(D \cdot (E+\bar{F}))} = \overline{(A \cdot B\bar{C})(\bar{D} + (E+\bar{F}))} = (A+B \cdot \bar{C})(\bar{D} + E + \bar{F})$$

### Question 2: (15 points)

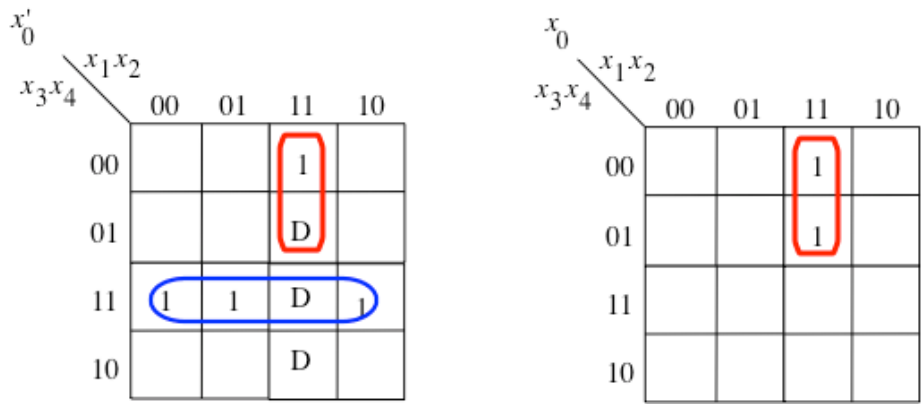
Minimize the cost of the following function  $F(x_0, x_1, x_2, x_3, x_4) = \Sigma(6, 7, 23, 24, 26, 28) + D(14, 22, 30)$ . Measure the cost of the minimized function by counting the total number of 2-input gates of the circuit (e.g.  $a*b + c*d$ , has cost of 3).

- a) Using Quine-McCluskey? (9 points)
- b) using Karnaugh (6 points)

**Solution:**

$$F(x_0, x_1, x_2, x_3, x_4) = \sum m(6, 7, 23, 24, 26, 28) + D(14, 22, 30)$$

a)



$$f(x_0, x_1, x_2, x_3, x_4) = \bar{x}_0 \cdot x_3 \cdot x_4 + \bar{x}_3 \cdot x_2 \cdot x_1$$

This form has a cost of 5.

b)

using Quine-McCluskey:

6	00110	✓
24	11000	✓
7	00111	✓
14	01110	✓
22	10110	✓
26	11010	✓
28	11100	✓
23	10111	✓
30	11110	✓

6,7 (1)	0011x	✓
6,14 (8)	0x110	✓
6,22 (16)	x0110	✓
24,26 (2)	110x0	✓
24,28 (4)	11x00	✓
7,23 (16)	x0111	✓
14,30 (16)	x1110	✓
22,23 (1)	1011x	✓
22,30 (8)	1x110	✓
26,30 (4)	11x10	✓
28,30 (2)	111x0	✓

6,7,22,23 (1,16)	x011x	p <sub>1</sub>
6,14,22,30 (8,16)	xx110	p <sub>2</sub>
24,26,28,30 (2,4)	11xx0	p <sub>3</sub>

Prime implicant	Minterm					
	6	7	23	24	26	28
p <sub>1</sub> = x011x	✓	✓	✓			
p <sub>2</sub> = xx110	✓					
p <sub>3</sub> = 11xx0				✓	✓	✓

P1, P3 are essential prime implicants and cover the function F resulting in the following form:

$$f(x_0, x_1, x_2, x_3, x_4) = \overline{x_0} \cdot x_3 \cdot x_4 + \overline{x_3} \cdot x_2 \cdot x_1$$

This form has a cost of 5.

**Question 3: (20 points)**

- Describe an unsigned binary multiplication between a 4-bit multiplier  $x_4x_3x_2x_1$  and a 4-bit multiplicand  $y_4y_3y_2y_1$ . (3 points)
- Draw the circuit for a 4-bit Array Multiplier and describe how it works. (10 points)
- Show the critical path of the 4-bit Array Multiplier? (3 points)
- Why is it faster than a serial multiplier? (4 points)

**Solution:**

- Lecture 11, slide 15
- Lecture 11, slide 18
- Lecture 11, slide 18

(Above mentioned lecture slides can be found at the end of this document)

d)

A serial multiplier checks the LSbit of the multiplier and accordingly adds the multiplicand, subsequently it shifts the multiplier. In total a multiplication of N-bits numbers needs N additions and N shifts of N-bit numbers.

Therefore, the serial multiplier would have a delay of:

$$N \cdot (\text{delay of N-bit addition} + \text{N-bit shift}) \geq N \cdot (\text{delay of N-bit addition}) \text{ which is} \\ \geq N \cdot \log N \cdot (\text{FA delay}), \text{ assuming a CLA or} \\ = N \cdot N \cdot (\text{FA delay}), \text{ assuming a ripple carry adder}$$

On the other hand the delay of the array multiplier is about  $2 \cdot N \cdot (\text{FA delay})$  and consequently it is faster.

**Question 4: (15 points)**

Consider a sequence detector circuit, which detects the sequence "01". It has one input W and one output Z (each of 1-bit). The output Z is equal to 1 if in two consecutive (immediately preceding) clock cycles the input was equal to 0 and then 1; otherwise the value of Z is equal to 0. All changes in the circuit occur on the positive edge of a clock signal.

e.g.

Clock cycle:	T0	T1	T2	T3	T4	T5	T6	T7	T8	T9
W:	0	1	0	1	1	0	0	0	1	1
Z:	0	0	1	0	1	0	0	0	0	1

- Draw the state diagram of the circuit. (2 point)
- Fill in the state table of the circuit and make a state assignment. (5 points)
- Draw the actual implementation of the circuit after extracting the Boolean functions of each D-flip-flop. (5 points)
- Did you create a Mealy or a Moore type of circuit? What is the difference between the two types? (2 points)
- What was your choice for the state-assignment? Why? (1 point)

**Solution:**

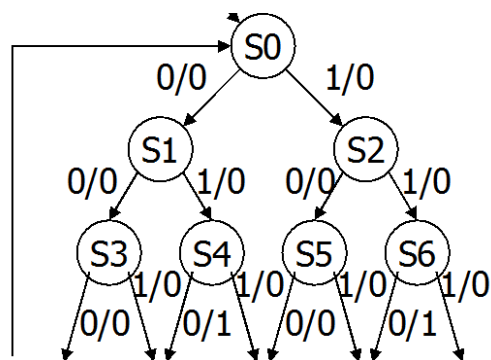
- similar to Lecture 4, slides 38-40
- similar to Lecture 4, slides 41-42
- similar to Lecture 4, slides 44-45

(Above mentioned lecture slides can be found at the end of this document)

- first part of the answer depends on your implementation. The output of a Moore type FSM depends only on the current state, while the output of a Mealy depends in addition to the input of the FSM.
- Depends on your state assignment. In general a binary or gray encoding would require less bits than a one-hot encoding, while the later would be faster. In some cases the binary would be slower than the gray encoding, but this depends on the state-diagram, how the transitions between states happen, and how can one “match” the output encoding with the state-assignment.

**Question 5: (8 points)**

Use partitioning to minimize the number of states in the following Finite State Machine (FSM).



- First create the state table of the FSM. (1 points)
- Minimize the number of state using partitioning. (5 points)
- Create the state table of the minimized version of the FSM. (1point)

d) Draw the state diagram of the minimized version of the FSM. (1point)

**Solution:**

Input Sequence	Present State	Next State		Output	
		X=0	X=1	X=0	X=1
Reset	S0	S1	S2	0	0
0	S1	S3	S4	0	0
1	S2	S5	S6	0	0
00	S3	S0	S0	0	0
01	S4	S0	S0	1	0
10	S5	S0	S0	0	0
11	S6	S0	S0	1	0

a)

b)

P1= (S0 S1 S2 S3 S4 S5 S6)

P2= (S0 S1 S2 S3 S5) (S4 S6)

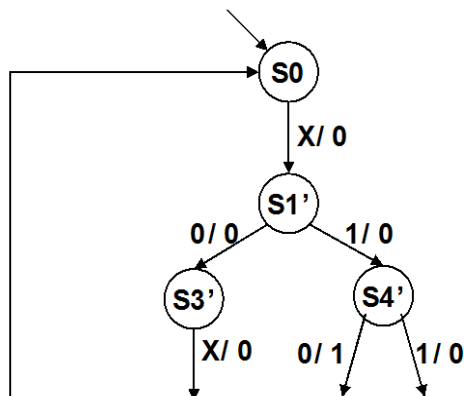
P3= (S0 S3 S5) (S1 S2) (S4 S6)

P4= (S0) (S3 S5) (S1 S2) (S4 S6)

c)

Input Sequence	Present State	Next State		Output	
		X=0	X=1	X=0	X=1
Reset	S0	S1'	S1'	0	0
0 + 1	S1'	S3'	S4'	0	0
X0	S3'	S0	S0	0	0
X1	S4'	S0	S0	1	0

d)



**Question 6: (9 points)**

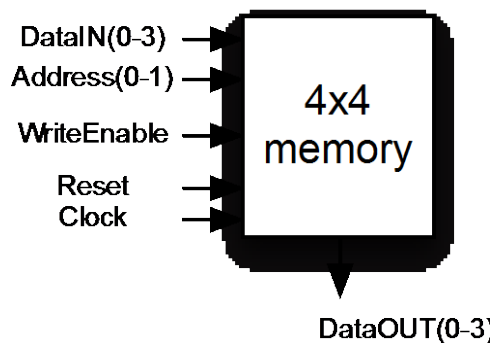
*(a) (6 points)*

Draw the block diagram of a 4x4 memory, using as “building blocks” D flip-flops and logic gates. The memory has the following inputs:

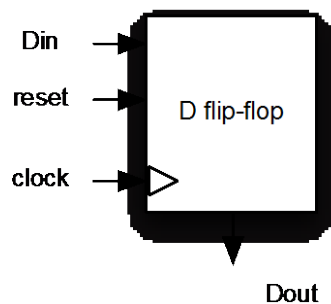
- $DataIN(0), DataIN(1), DataIN(2), DataIN(3),$
- *Write-enable,*
- $Address(0), Address(1)$
- *Reset, Clock*

And the following outputs:

- $DataOUT(0), DataOUT(1), DataOUT(2), DataOUT(3),$



The D flip-flop has the following interface:



*(b) (3 points)*

Taking the above 4x4 memory as a black box (not having the ability to change its internal design) what can we add to use it as a 16x1 memory?

**Solution:**

- lecture 11, slide 34 (but for 4x4 instead of 4x3)
- a column multiplexer as shown in lecture 11, slide 39

(Above mentioned lecture slides can be found at the end of this document)

**Question 7: (5 points)**

*Explain the advantages and disadvantages of the following computing alternatives:*

- 1. ASICs (Application Specific Integrated Circuits)*
- 2. Field Programmable gate Arrays (FPGAs)*
- 3. General Purpose processors (running software)*

**Solution:**

*Lecture 12 Slide3*

(Above mentioned lecture slides can be found at the end of this document)

**Question 8: (12 points)**

*Explain the timing constraints of a D flip-flop.*

- a) What is the propagation time, setup time and hold time? (6 points)*
- b) Make a timing diagram to show the above time constraints in a D flip-flop. (3 points)*
- c) Explain when a flip-flop may enter a metastable state. (3 points)*

**Solution:**

- a) In lecture 16 slide 18*
- b) something similar to lecture 16 slide 19*
- c) In lecture 16 slide 31*

(Above mentioned lecture slides can be found at the end of this document)

**Question 9: (6 points)**

- a) Explain the difference between permanent, transient and intermittent faults. (3 points)*
- b) Name at least 2 causes for each type of faults. (3 points)*

**Solution:**

*In lecture 13 slide 5*

(Above mentioned lecture slides can be found at the end of this document)

**Question 10: (5 points)**

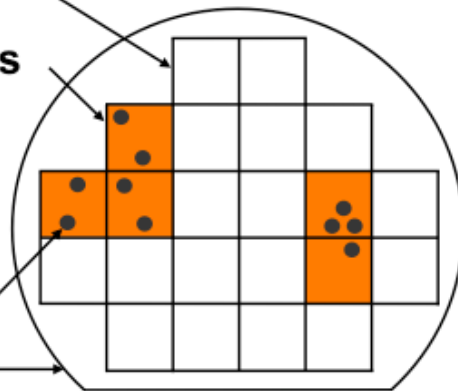
What is the yield for the following wafer:

**Good chips**

**Faulty chips**

**Defects**

**Wafer**



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**Solution:**

*Lecture 13 slide 10*

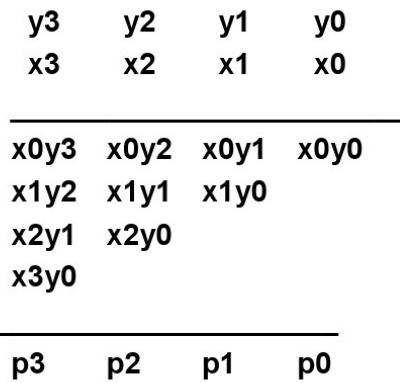
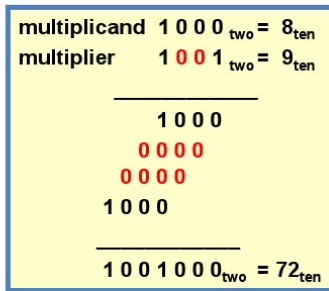
(Above mentioned lecture slides can be found at the end of this document)

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Question 3:

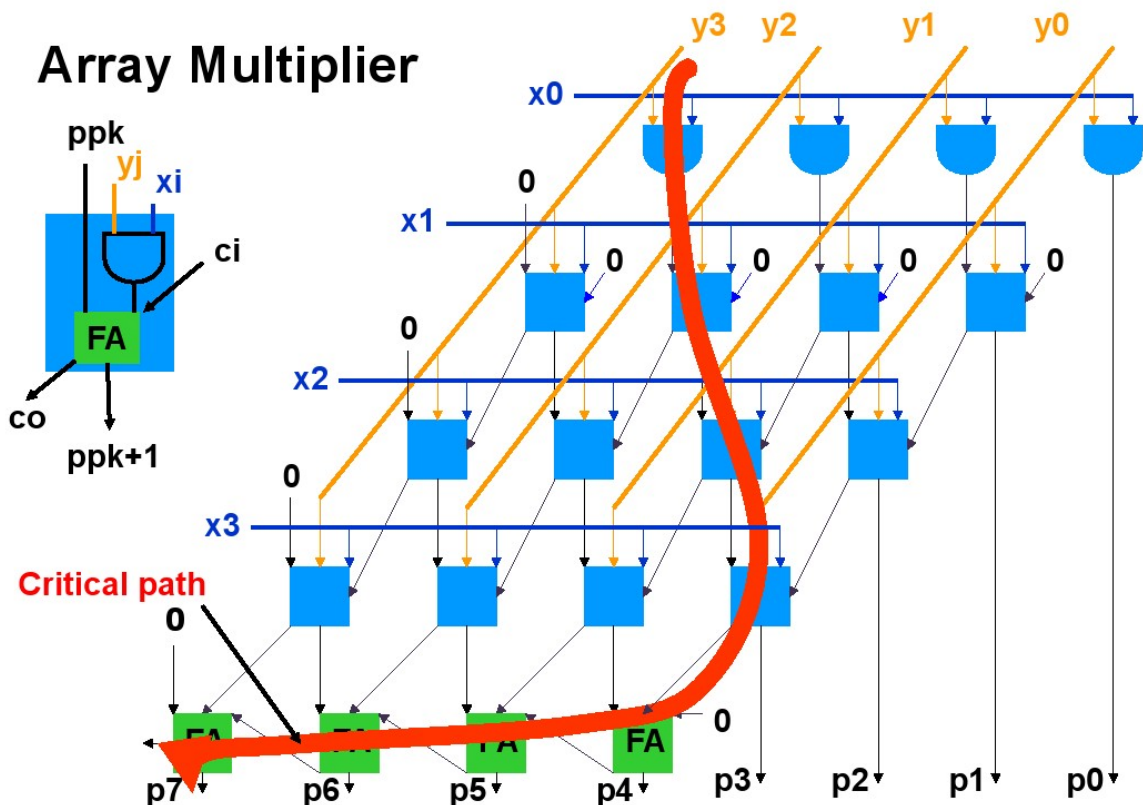
# Adding Partial Products



multiplicand  
 multiplier  
  
 four  
 partial  
 products  
 to be  
 summed

*Requires three 4-bit additions. Slow.*

## Array Multiplier



Question 4:

## Manual design steps (1): specifications

### Specifications:

1. the circuit has one input,  $w$ , and one output,  $z$ .
2. all changes in the circuit occur on the positive edge of a clock signal.
3. the output  $z$  is equal to 1 if during two immediately preceding clock cycles the input  $w$  was equal to 1. otherwise, the value of  $z$  is equal to 0.

Clockcycle:	$t_0$	$t_1$	$t_2$	$t_3$	$t_4$	$t_5$	$t_6$	$t_7$	$t_8$	$t_9$	$t_{10}$
$w$ :	0	1	0	1	1	0	1	1	1	0	1
$z$ :	0	0	0	0	0	1	0	0	1	1	0

## Manual design steps (2): state diagram

- *starting* state **A**: when power is on or *reset* signal is applied.
- As long as  $w$  is 0, it remains in **A**.
- After  $w \rightarrow 1$ , it moves to state **B**.
- Then,
  - If  $w \rightarrow 0$ , it moves back to state **A**.
  - If  $w \rightarrow 1$ , it moves to state **C**, and  $z=1$ .
- When in state **C**,
  - If  $w \rightarrow 0$ , back to state **A**, and  $z=0$ ;
  - If  $w \rightarrow 1$ , remain in state **C**.

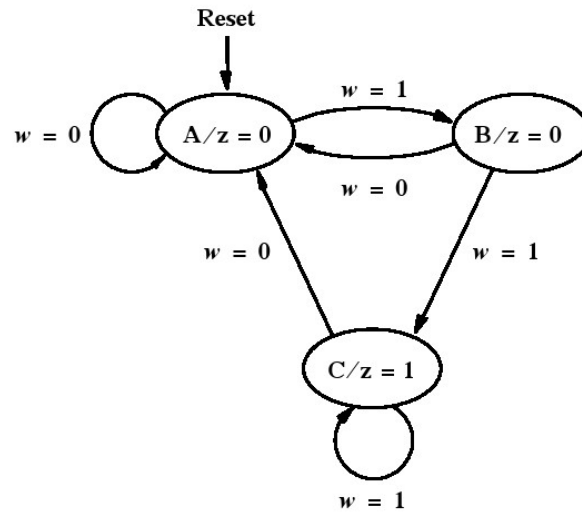


Figure 8.3. State diagram of a simple sequential circuit.

## Manual design steps (3): state table

From the state diagram, we have the state table

**Flip-flops**

Present state	Next state		Output $z$
	$w = 0$	$w = 1$	
A	A	B	0
B	A	C	0
C	A	C	1

**Combinational circuit**

# Manual design steps (4): state assignment

	Present state $y_2 y_1$	Next state		Output $z$
		$w = 0$	$w = 1$	
		$Y_2 Y_1$	$Y_2 Y_1$	
A	00	00	01	0
B	01	00	10	0
C	10	00	10	1
	11	<i>dd</i>	<i>dd</i>	<i>d</i>

A: 00  
B: 01  
C: 10

# Manual design steps (5): implementation

From state-assigned table: we have the following Karnaugh maps

		$y_2 y_1$	00	01	11	10
$w$	0		0	0	d	0
	1		1	0	d	0

$$Y_1 = w \bar{y}_1 \bar{y}_2$$

		$y_1$	0	1
$y_2$	0		0	0
	1		1	d

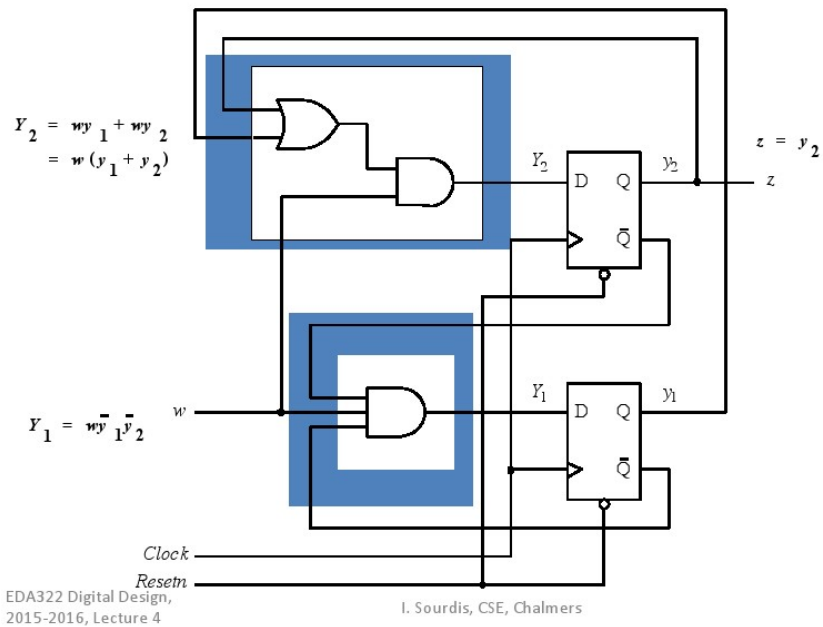
$$z = y_2$$

		$y_2 y_1$	00	01	11	10
$w$	0		0	0	d	0
	1		0	1	d	1

$$Y_2 = w y_1 + w y_2$$

$$= w (y_1 + y_2)$$

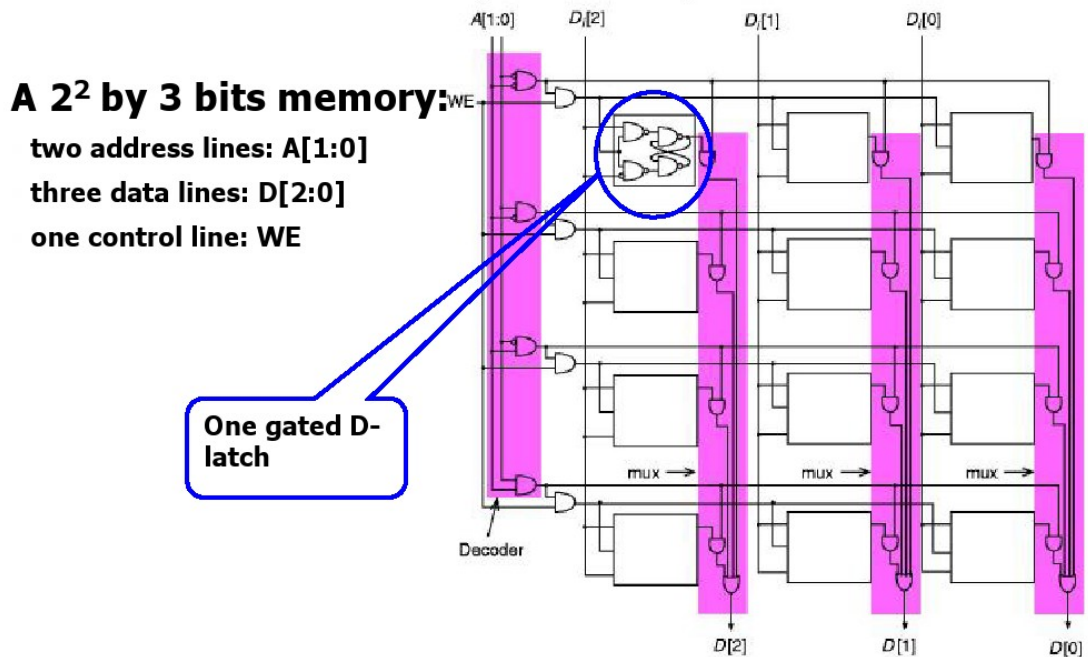
# Final implementation



45

Question 6:

# Memory Example



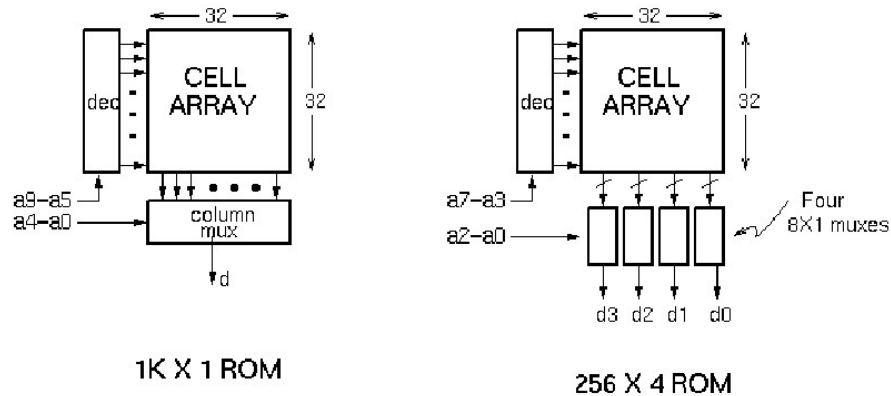
EDA322 Digital Design, 2015-2016, Lecture 11

I. Sourdis, CSE, Chalmers

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# Column MUX in ROMs and RAMs:

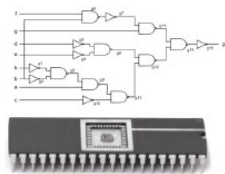
- Controls physical aspect ratio
- In DRAM, allows reuse of chip address pins



## Question 7:

# Computing alternatives

Hardware  
(Application Specific  
Integrated Circuits)



### Advantages:

- very high performance and efficient

### Disadvantages:

- not flexible (can't be altered after fabrication)
- High NRE Cost

Reconfigurable  
computing



### Advantages:

- much higher performance than software / lower performance than ASIC
- higher level of flexibility than hardware / more difficult to program than SW

•fills the gap between hardware and software

Software-programmed  
processors

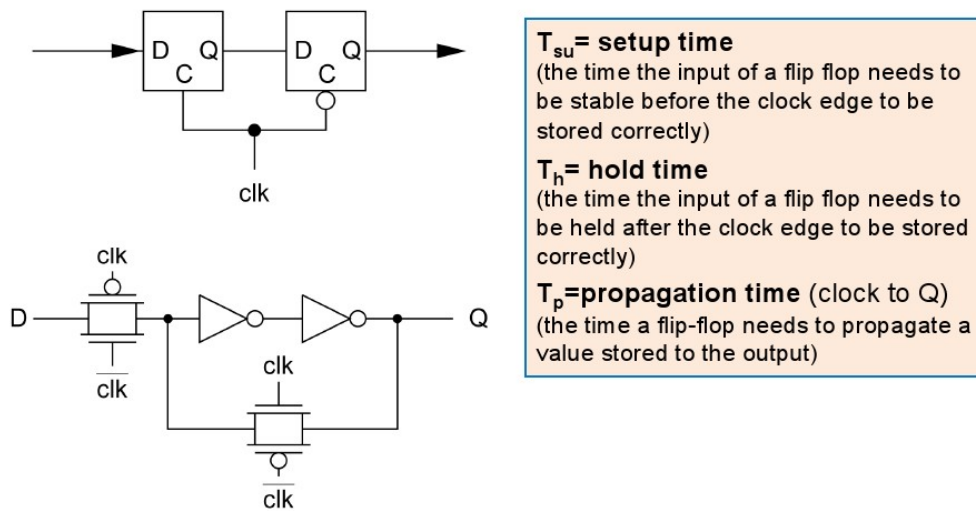


### Advantages:

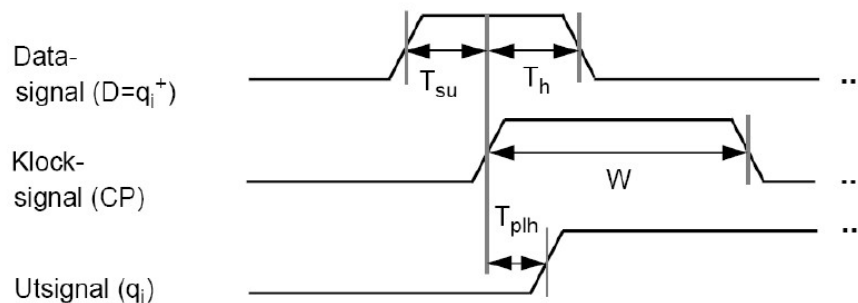
- software is very flexible to change
- ### Disadvantages:
- performance can suffer if clock is not fast
  - fixed instruction set by hardware

**Question 8:**

## Delay in Flip-flops

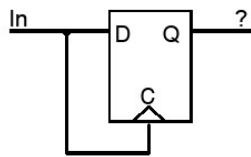


## Time parameters for clocked memory elements



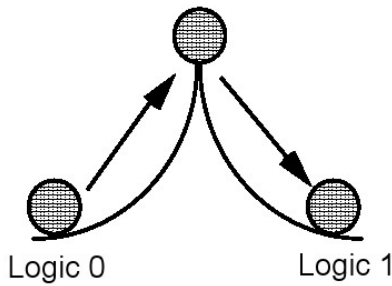
# Metastability and Asynchronous Inputs

## Synchronizer Failure

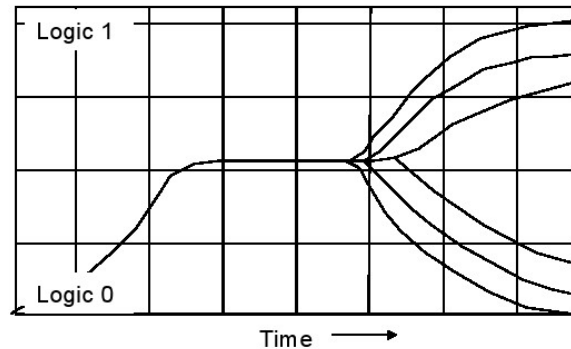


When FF input changes close to clock edge, the FF may enter the *metastable* state: neither a logic 0 nor a logic 1

It may stay in this state an indefinite amount of time, although this is not likely in real circuits



Small, but non-zero probability that the FF output will get stuck in an in-between state



Oscilloscope Traces Demonstrating Synchronizer Failure and Eventual Decay to Steady State

## Question 9:

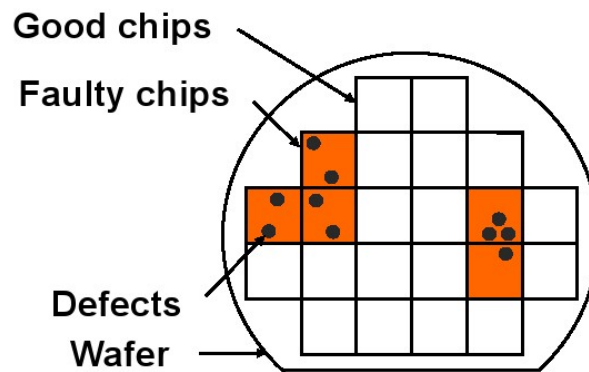
# Types of Faults

- **Transient faults**
  - Faults that happen only once
    - and it's VERY unlikely to happen again
  - Causes:
    - Electromagnetic Interference
      - Neighbors mobile phone
      - Static electricity
    - Various particles hitting the silicon surface
      - Heavy ions such as iron,  $\alpha$ -particles, neutrons.
    - Internal effects
      - Crosstalk, metastability, power supply disturbances
- **Permanent faults**
  - Faults that are always there
  - Causes:
    - Design defects
    - Manufacturing defects
    - Transistor aging
- **Intermittent faults**
  - Faults that come and go (probably periodically)
  - Causes: Variations
    - **Static**: transistors on a chip may not be exactly the same although they were supposed to be
    - **Dynamic**: temperature changes



Question 10:

## Circuit Fabrication and Defects



Defects are permanent faults caused during the Manufacturing process

$$\text{yield} = \frac{\text{number of working chips produced}}{\text{Total number of chips produced}}$$

$$\text{Wafer yield} = 17/22 = 0.77$$